

## FDD8444

# N-Channel PowerTrench<sup>®</sup> MOSFET

## 40V, 50A, 5.2m $\Omega$

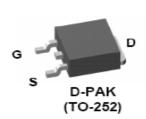
### Features

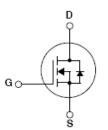
- Typ  $r_{DS(on)}$  = 4m $\Omega$  at V<sub>GS</sub> = 10V, I<sub>D</sub> = 50A
- Typ Q<sub>g(10)</sub> = 89nC at V<sub>GS</sub> = 10V
- Low Miller Charge
- Low Q<sub>rr</sub> Body Diode
- UIS Capability (Single Pulse/ Repetitive Pulse)
- Qualified to AEC Q101
- RoHS Compliant



### Applications

- Automotive Engine Control
- Powertrain Management
- Solenoid and Motor Drivers
- Electronic Transmission
- Distributed Power Architecture and VRMs
- Primary Switch for 12V Systems





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March 2015

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## **MOSFET Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Ratings	Units
V <sub>DSS</sub>	Drain to Source Voltage	40	V
V <sub>GS</sub>	Gate to Source Voltage	±20	V
	Drain Current Continuous (V <sub>GS</sub> = 10V) (Not	e 1) 145	
Continuous (V <sub>GS</sub> = 10V, with $R_{\theta JA} = 52^{\circ}C/W$ )		20	Α
	Pulsed	Figure 4	
E <sub>AS</sub>	Single Pulse Avalanche Energy (Not	e 2) 535	mJ
<b>D</b>	Power Dissipation	153	W
PD	Derate above 25°C	1.02	W/ºC
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55 to +175	°C

### **Thermal Characteristics**

$R_{\thetaJC}$	Thermal Resistance, Junction to Case	0.98	°C/W
$R_{\thetaJA}$	Thermal Resistance, Junction to Ambient TO-252, 1in <sup>2</sup> copper pad area	52	°C/W

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD8444	FDD8444	TO-252AA	13"	16mm	2500 units

**Electrical Characteristics**  $T_J = 25^{\circ}C$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units

#### **Off Characteristics**

<b>B<sub>VDSS</sub></b>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250μA, V <sub>GS</sub> =	$I_{\rm D}$ = 250 $\mu$ A, $V_{\rm GS}$ = 0V		-	-	V
1	Zoro Gato Voltago Drain Current	V <sub>DS</sub> = 32V		-	-	1	uА
DSS	I <sub>DSS</sub> Zero Gate Voltage Drain Current	$V_{GS} = 0V$	T <sub>J</sub> = 150 <sup>o</sup> C	-	-	250	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA

#### **On Characteristics**

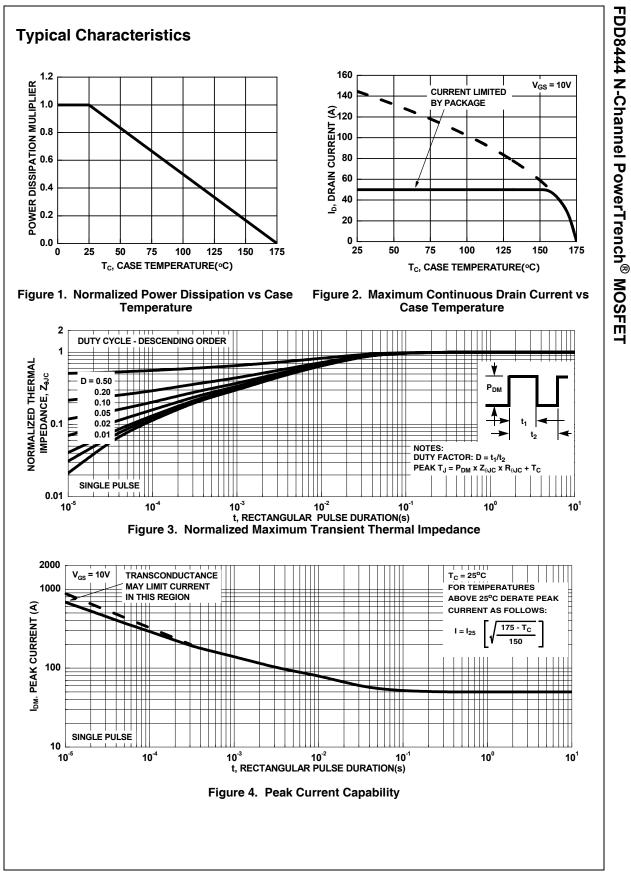
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2	2.5	4	V
		I <sub>D</sub> = 50A, V <sub>GS</sub> = 10V	-	4	5.2	
r <sub>DS(on)</sub>	Drain to Source On Resistance	I <sub>D</sub> = 50A, V <sub>GS</sub> = 10V, T <sub>J</sub> = 175 <sup>o</sup> C	-	7.2	9.4	mΩ

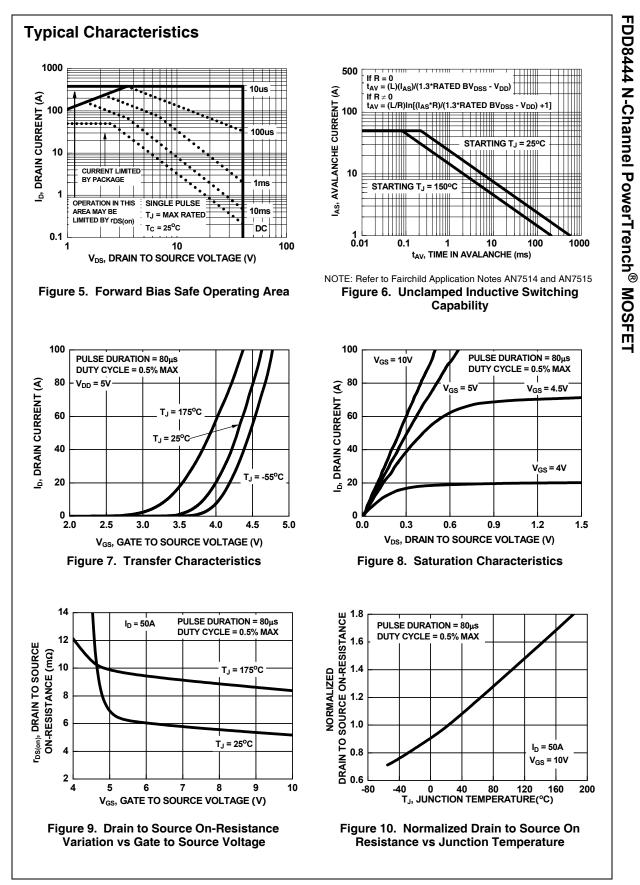
#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance		0.4	-	6195	-	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V, f = 1MHz		-	585	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance				332	-	pF
R <sub>G</sub>	Gate Resistance	f = 1MHz	f = 1MHz		1.9	-	Ω
Q <sub>g(TOT)</sub>	Total Gate Charge at 10V	V <sub>GS</sub> = 0 to 10V		-	89	116	nC
Q <sub>g(5)</sub>	Total Gate Charge at 5V	$V_{GS}$ = 0 to 5V			43	56	nC
Q <sub>g(TH)</sub>	Threshold Gate Charge	$V_{GS}$ = 0 to 2V	V <sub>DD</sub> = 20V I <sub>D</sub> = 50A	-	11	14.3	nC
Q <sub>gs</sub>	Gate to Source Gate Charge		$I_0 = 30A$ $I_0 = 1.0mA$	-	23	-	nC
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau	I <sub>g</sub> – 1.011A		-	11	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge			-	20	-	nC

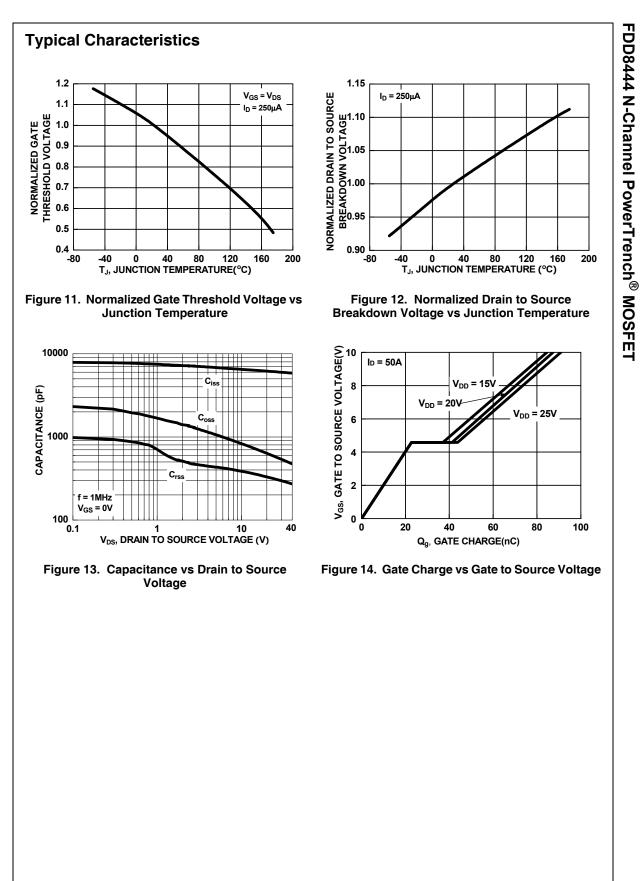
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
witch	ning Characteristics					
on	Turn-On Time		-	-	135	ns
l(on)	Turn-On Delay Time		-	12	-	ns
	Turn-On Rise Time	$V_{DD} = 20V, I_D = 50A$	-	78	-	ns
l(off)	Turn-Off Delay Time	V <sub>GS</sub> = 10V, R <sub>GS</sub> = 2Ω	-	48	-	ns
	Turn-Off Fall Time		-	15	-	ns
off	Turn-Off Time		-	-	95	ns
rain-S	ource Diode Characteristics	i				
SD	Source to Drain Diode Voltage	I <sub>SD</sub> = 50A	-	0.9	1.25	v
		I <sub>SD</sub> = 25A	-	0.8	1.0	
r	Reverse Recovery Time	I <sub>F</sub> = 50A, dI <sub>F</sub> /dt = 100A/μs	-	39	51	ns
rr	Reverse Recovery Charge	F, F (	-	45	59	nC
otes: Package o Starting T	current limitation is 50A. <sub>J</sub> = 25°C, L = 0.67mH, I <sub>AS</sub> = 40A					
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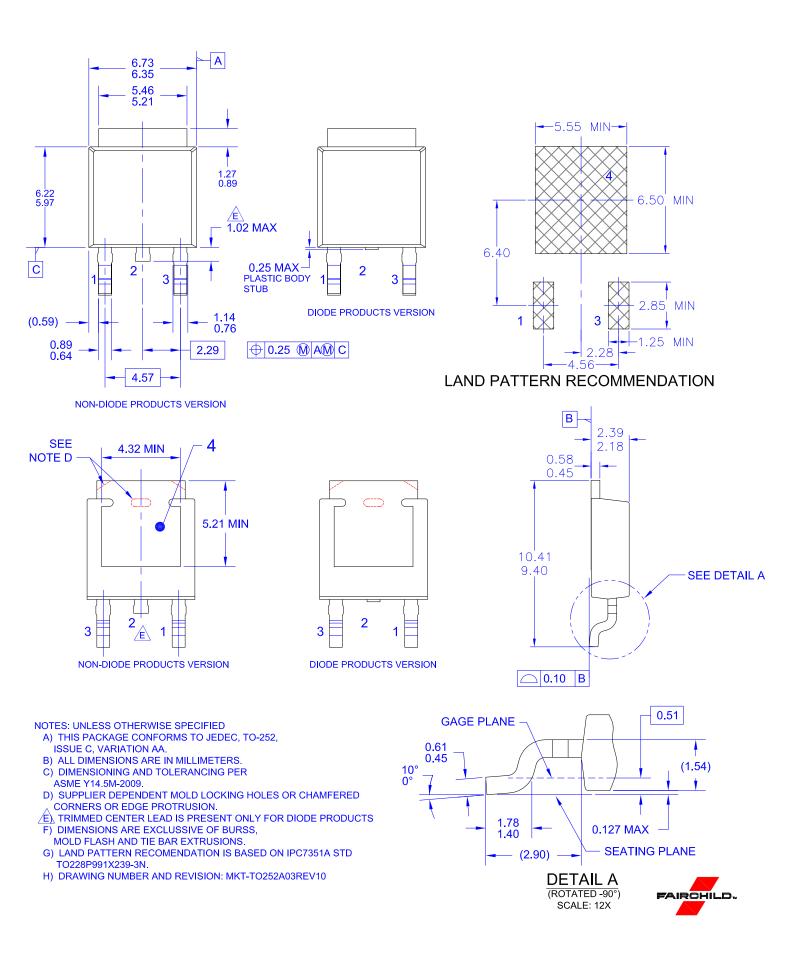
This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry. For a copy of the requirements, see AEC Q101 at: http://www.aecouncil.com/ All Fairchild Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

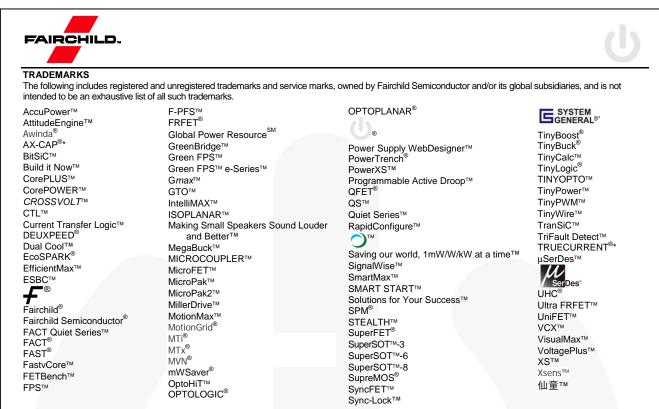




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